

Workshop R&D Virgo, Institut Fresnel, Marseille, 4-6 mars 2024

# Caractérisation composants Lumière diffusée, bruit thermique

Michel LEQUIME and Myriam ZERRAD

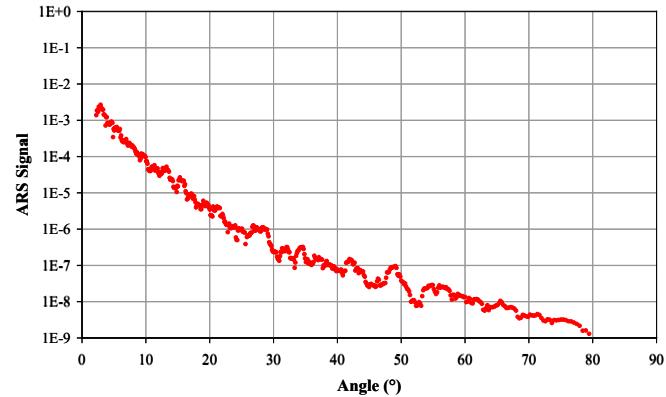
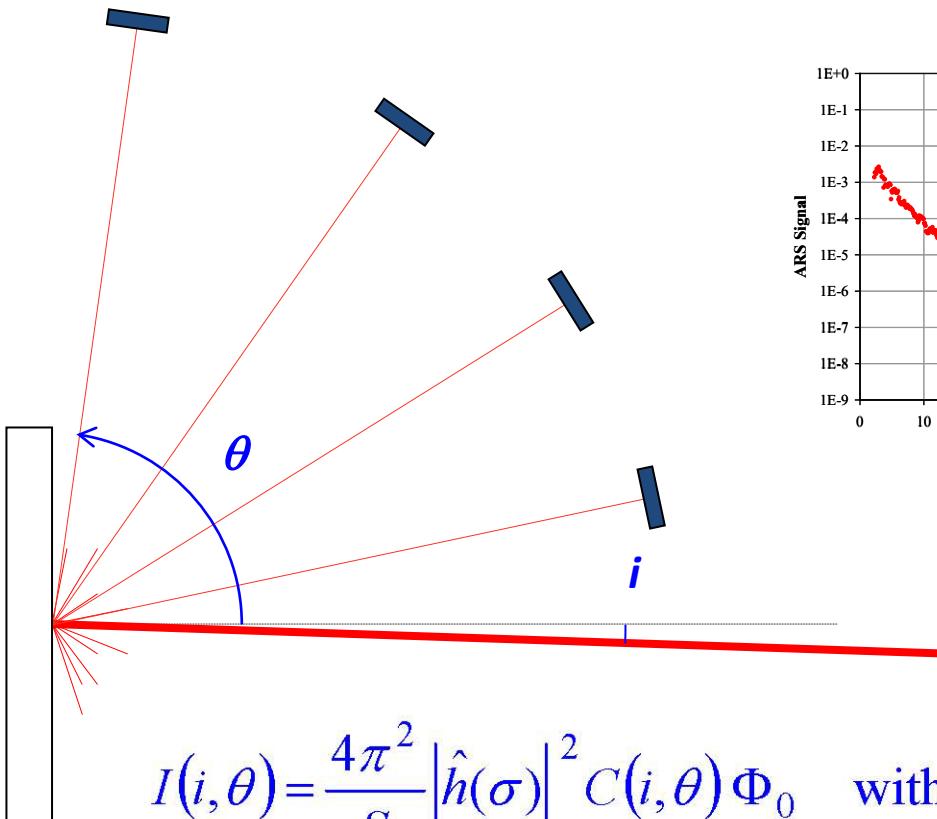
# Outline

## ■ 3 key R&D topics

- *Develop an improved version of **SPARSE** capable of detecting the presence of **point defects** on the surface of a **large diameter substrate**, coated or uncoated, and determining the contribution of these defects to scattering loss budget.*
- *Develop an improved version of **BARRITON** capable of detecting the axial position and strength of retroreflection and/or **backscatter sources** along the optical axis of a **large instrument**.*
- *Development of a compact and **adjustment free** interferometric instrument for the measurement of the **thermal noise** of an optical interference coating (**GRAVITERM**).*

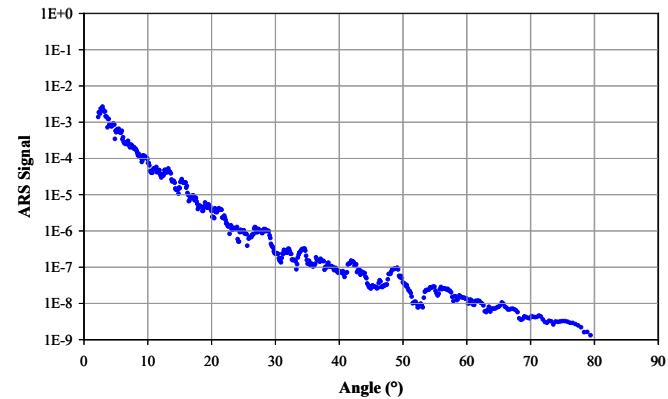
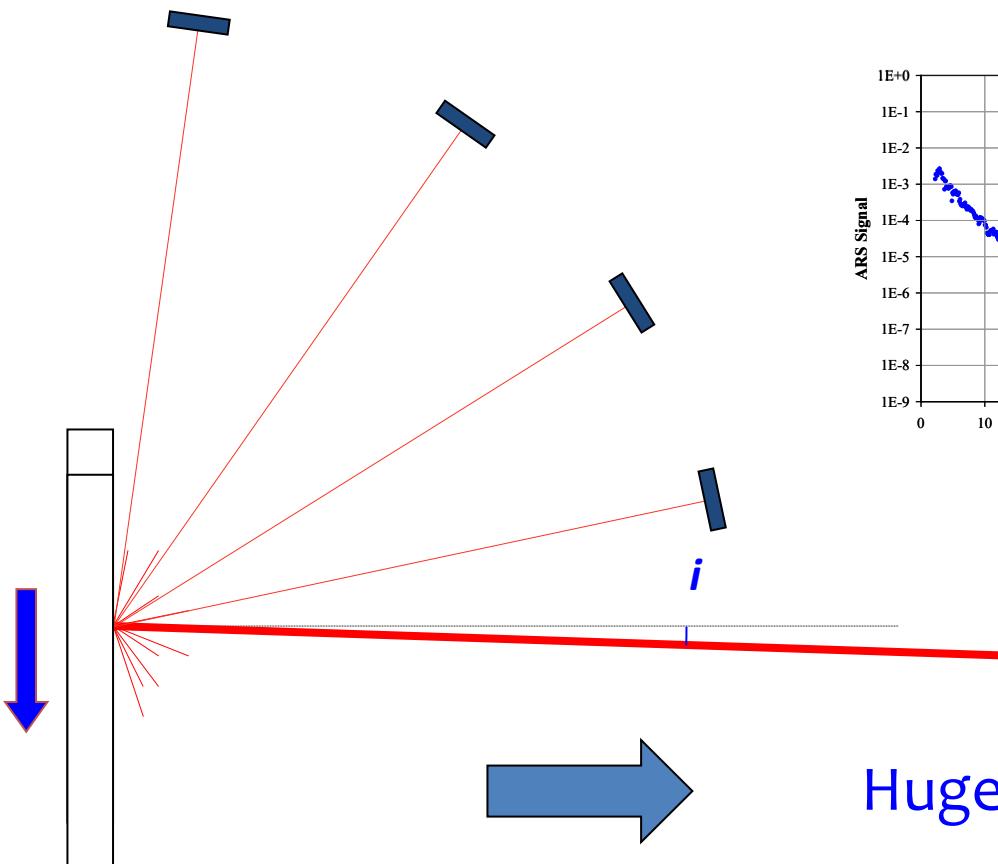
# SPARSE – Point Defects

- BRDF measurement - Standard configuration



# SPARSE – Point Defects

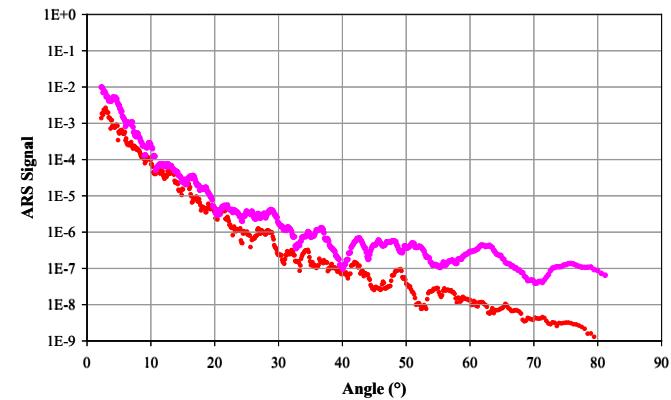
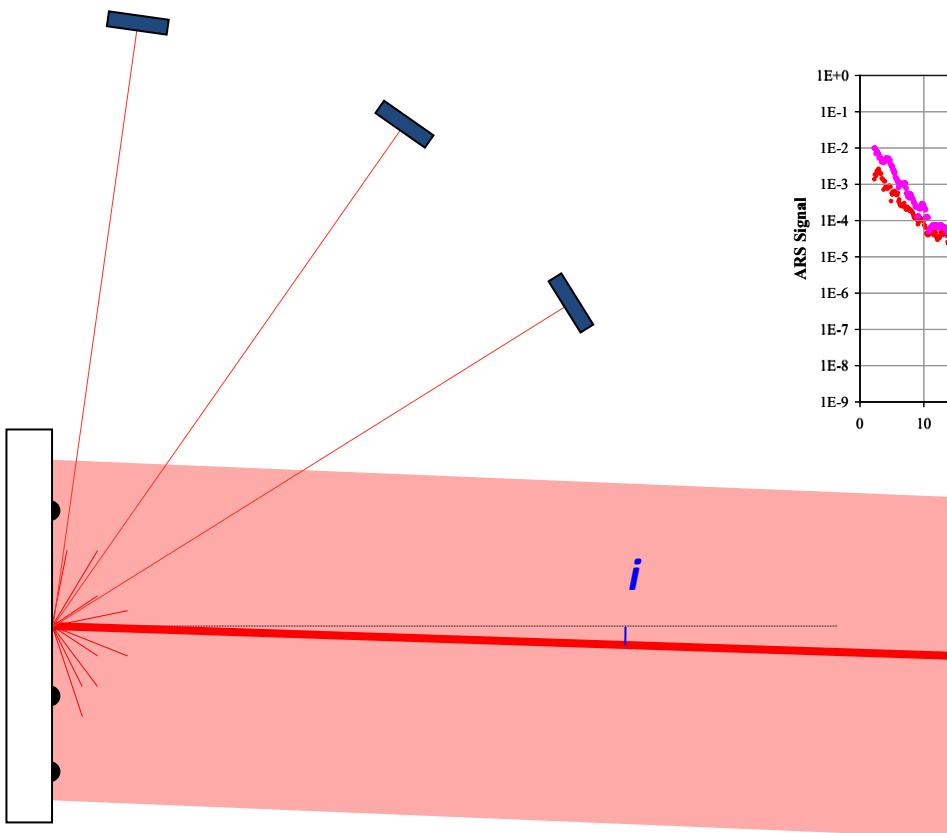
- BRDF measurement - Spatial sample scan configuration



Huge time required for acquisition

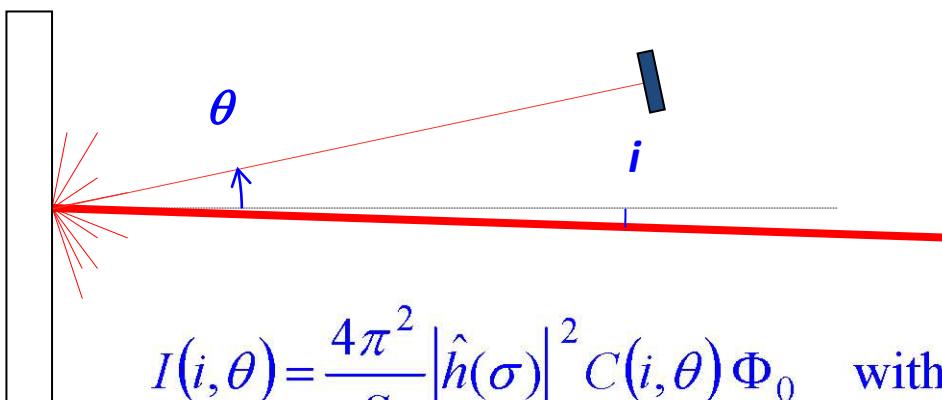
# SPARSE – Point Defects

- BRDF measurement - Extended beam configuration



# SPARSE – Point Defects

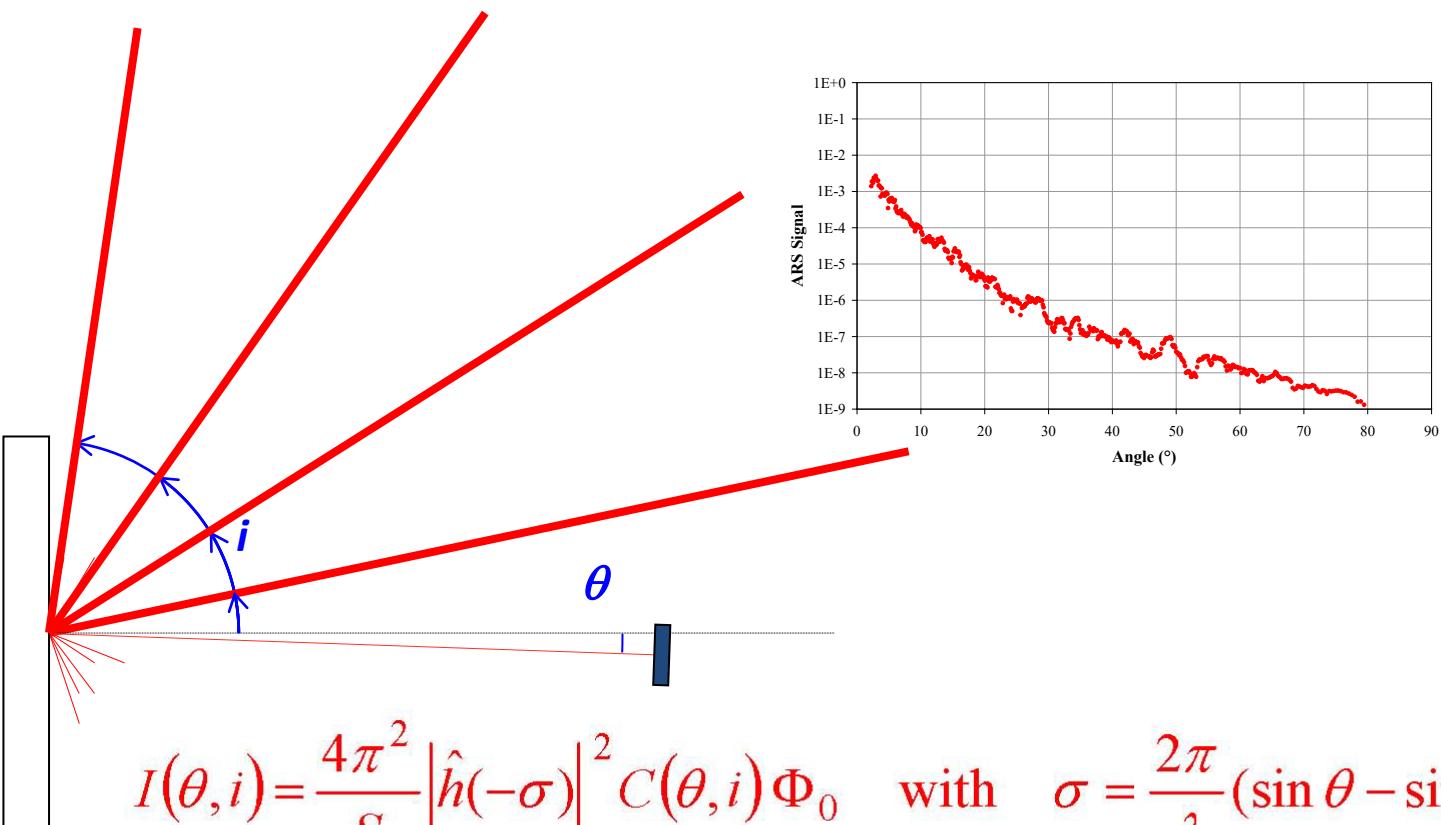
- BRDF measurement – Standard configuration



$$I(i, \theta) = \frac{4\pi^2}{S} |\hat{h}(\sigma)|^2 C(i, \theta) \Phi_0 \quad \text{with} \quad \sigma = \frac{2\pi}{\lambda} (\sin \theta - \sin i)$$

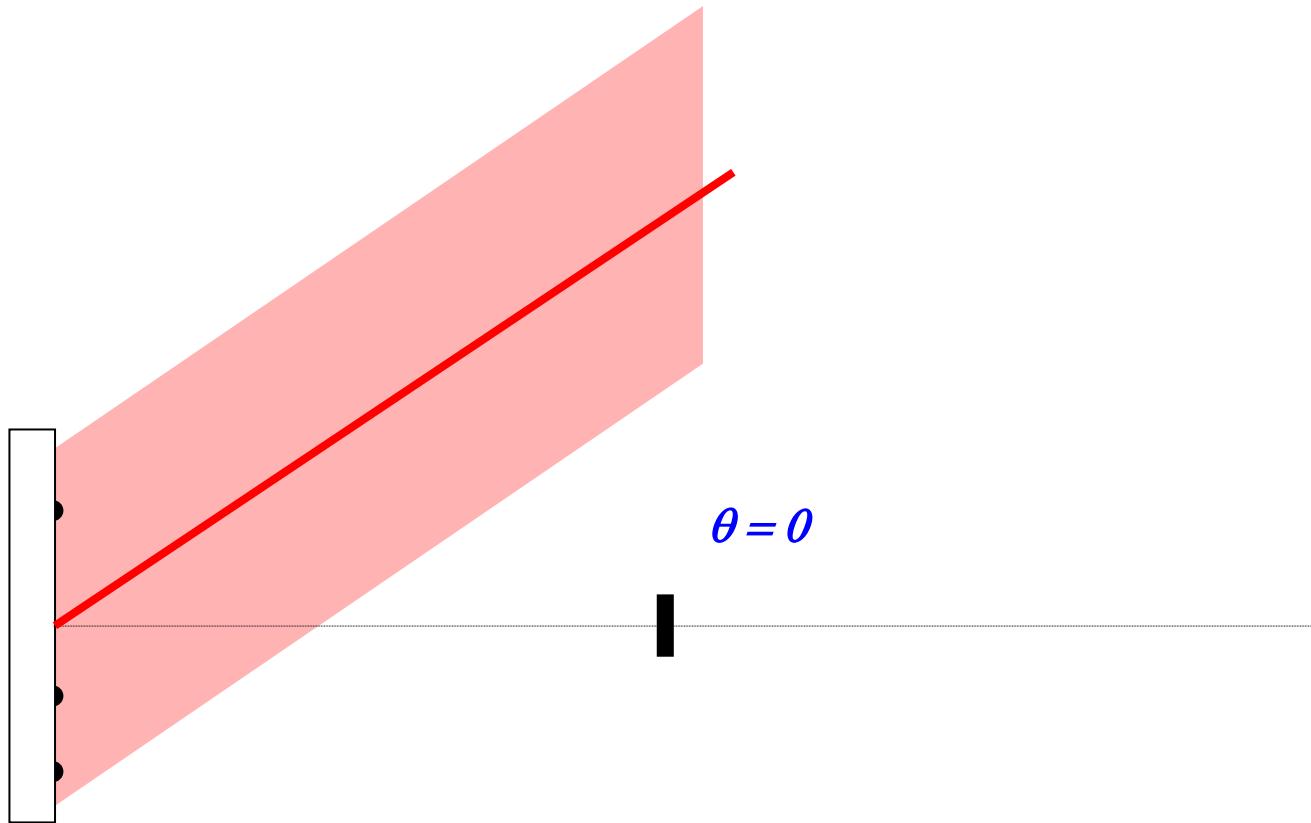
# SPARSE – Point defects

- BRDF measurement - Reverse configuration



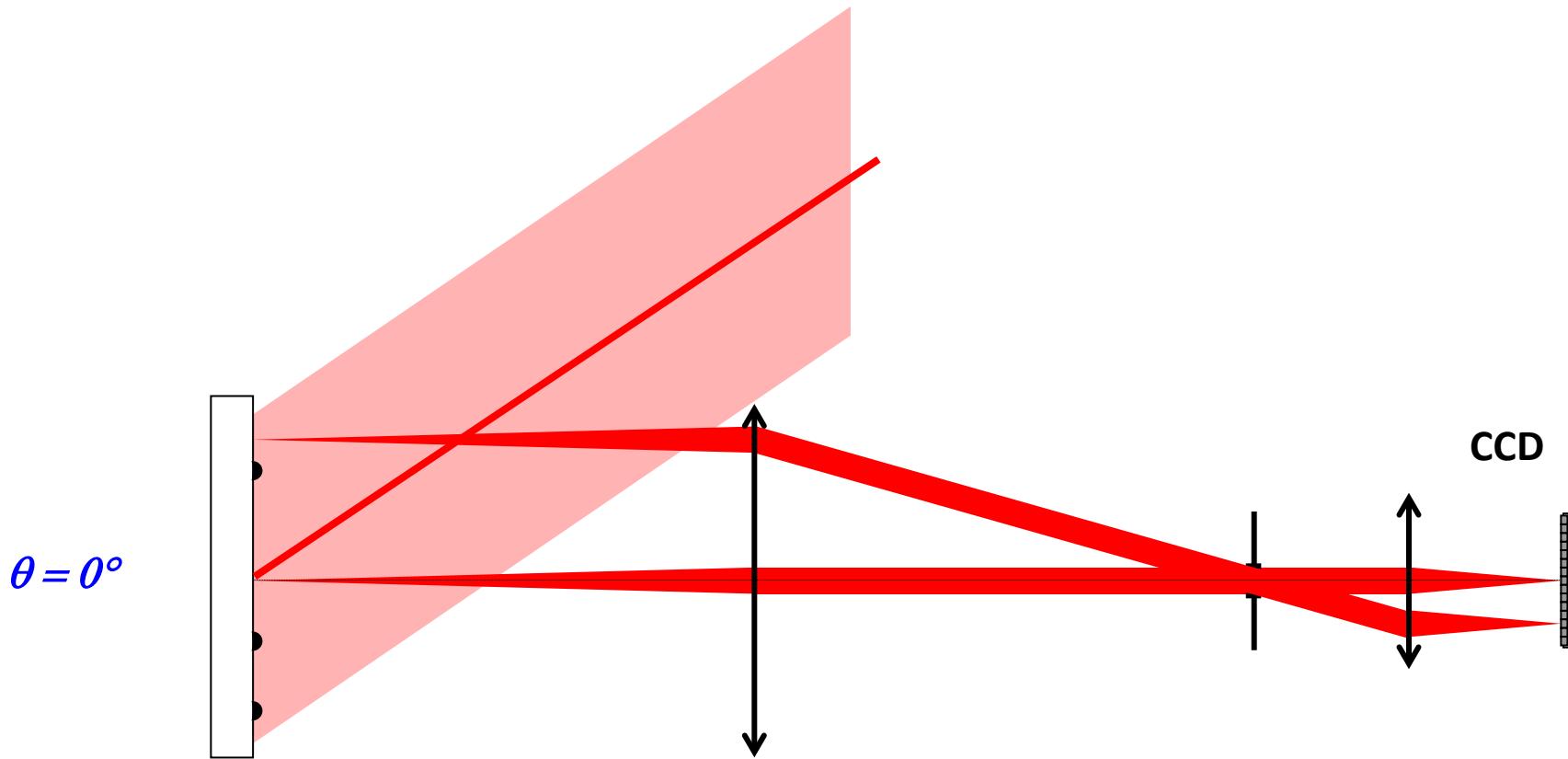
# SPARSE – Point Defects

- BRDF measurement - Reverse configuration with extended beam



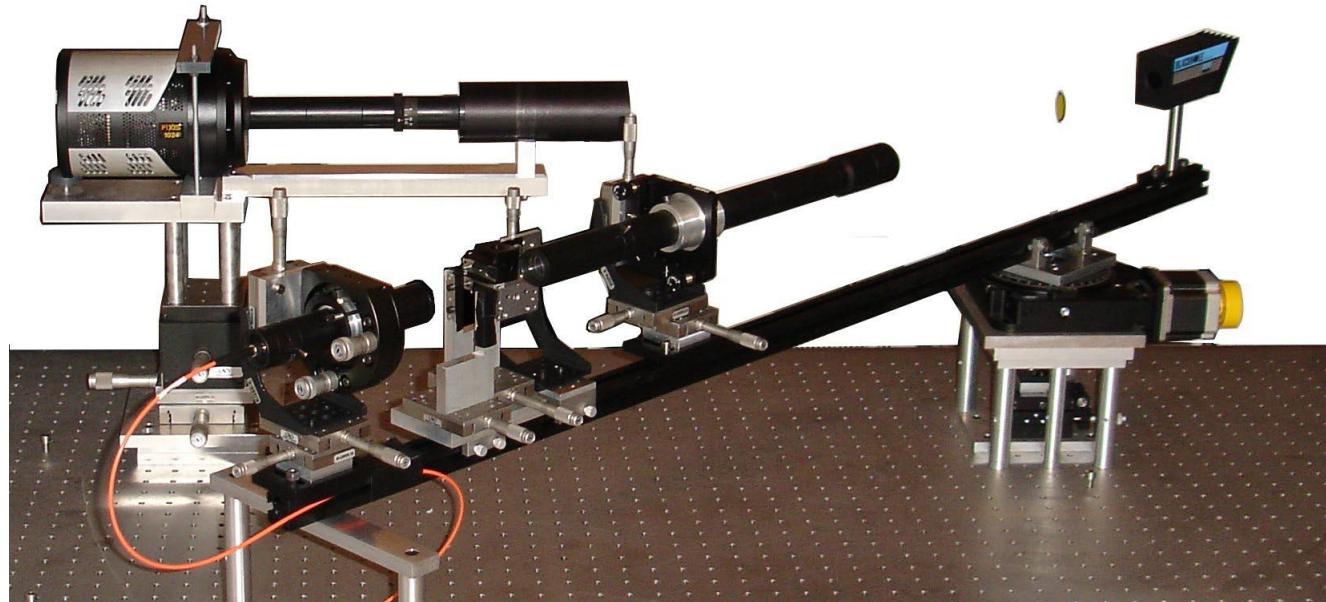
# SPARSE – Point Defects

- BRDF measurement - Reverse configuration with extended beam and photodetector array



# SPARSE – Point defects

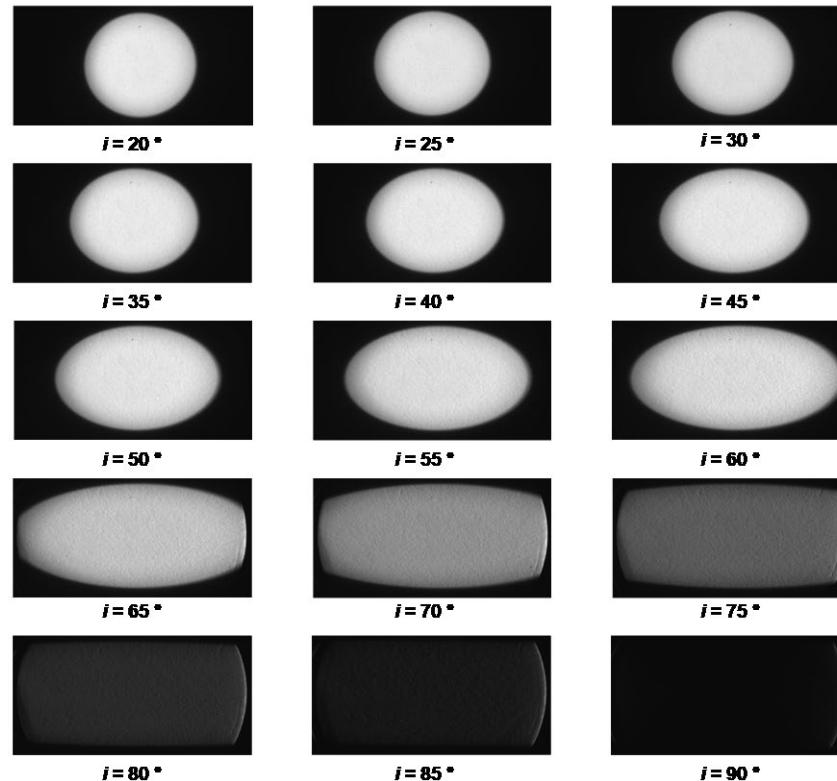
- Reverse configuration with extended beam and photodetector array



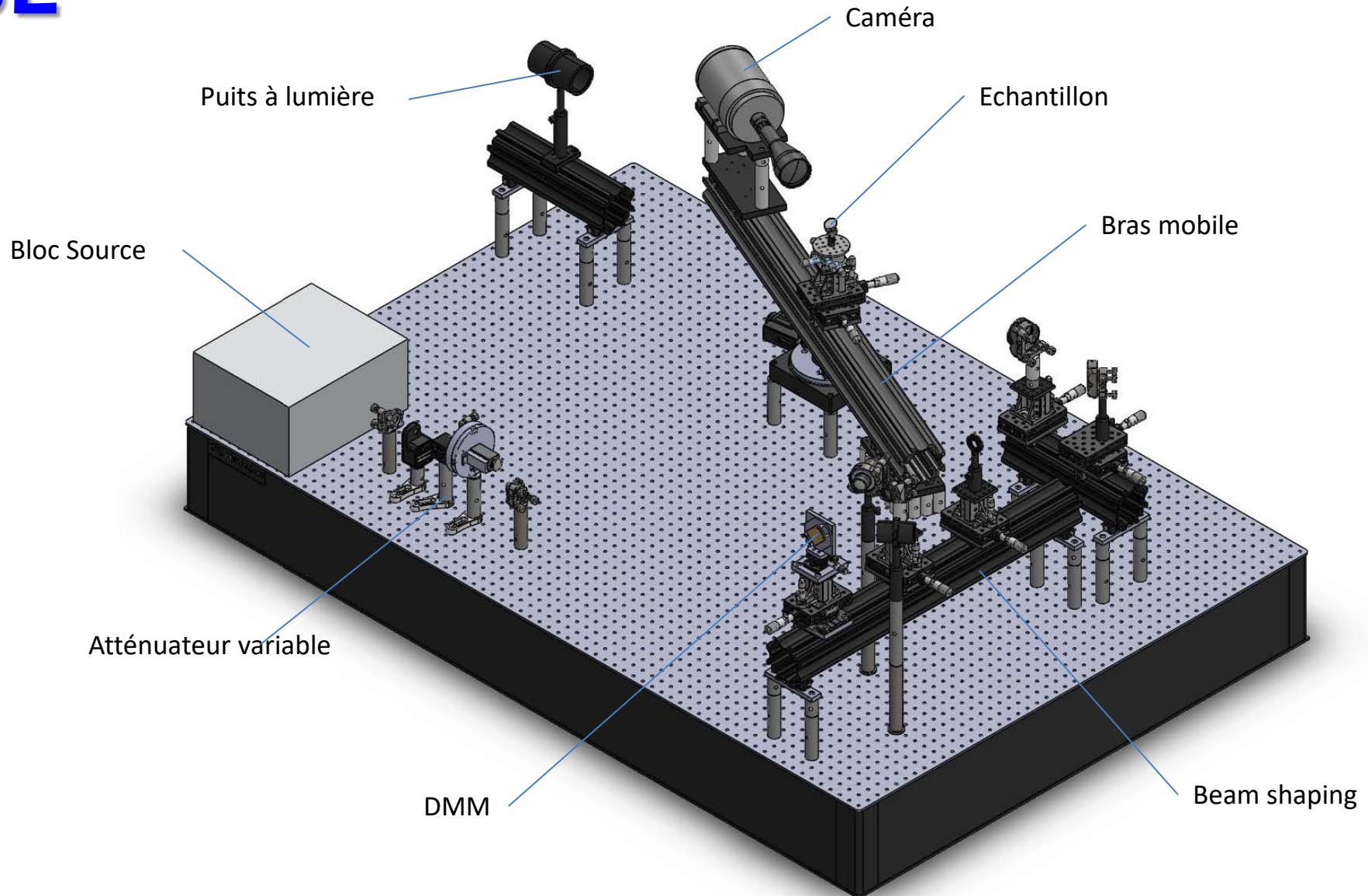
M. Lequime, M. Zerrad, C. Deumié, and C. Amra, "A goniometric light scattering instrument with high-resolution imaging," Opt. Commun. **282**, 1265-1273 (2009)

# SPARSE – Point Defects

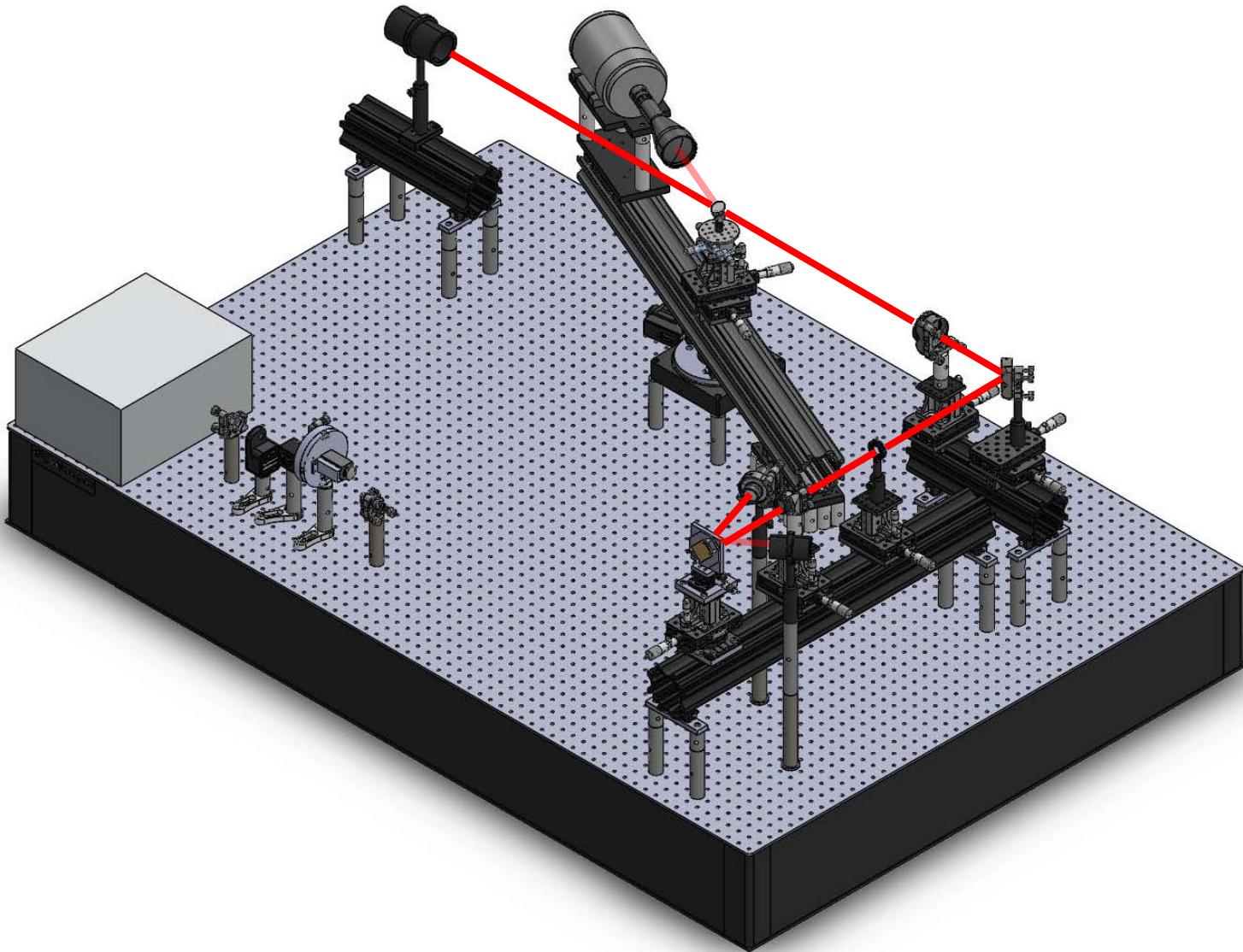
- Problem: continuous distortion of the illuminated area



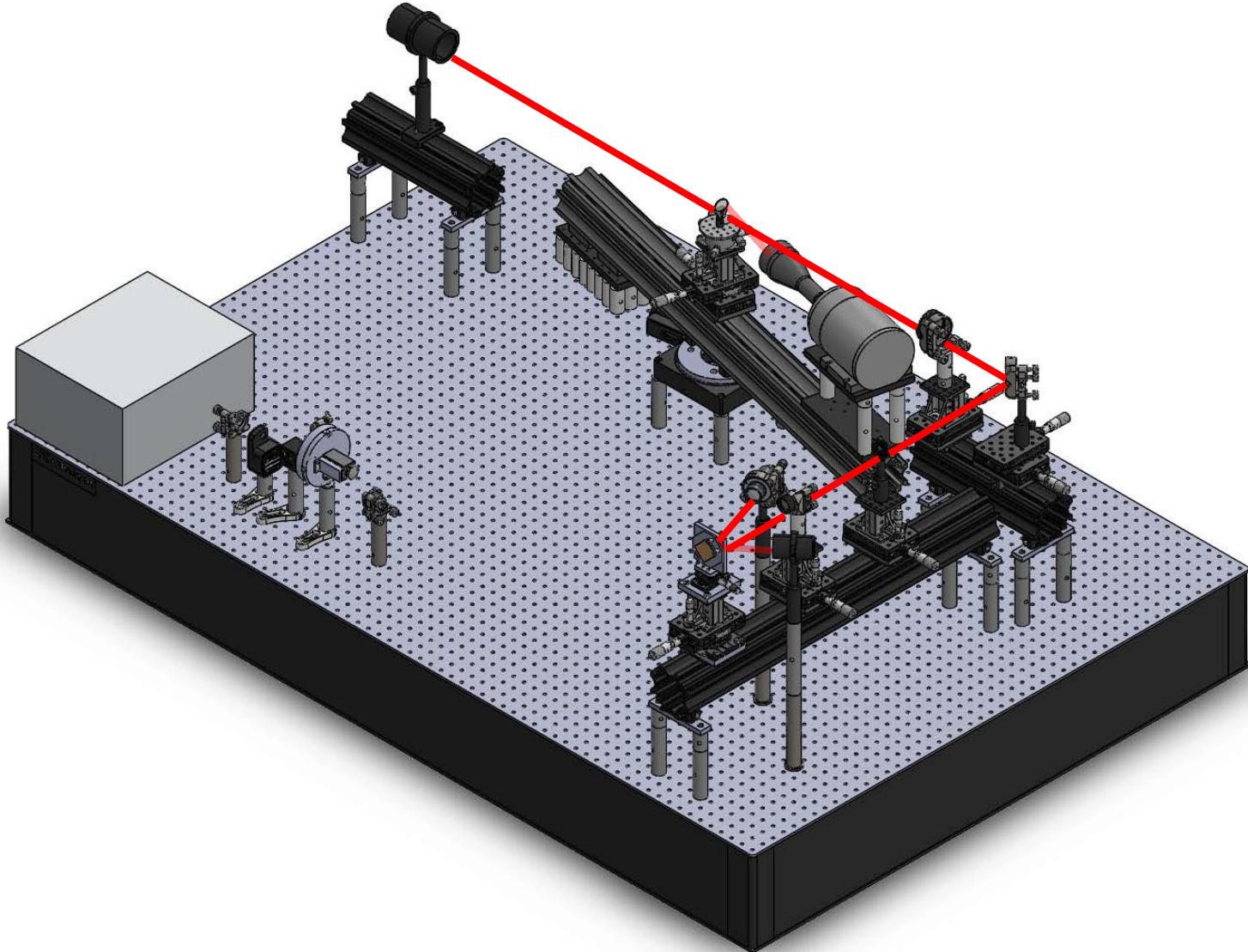
# SPARSE



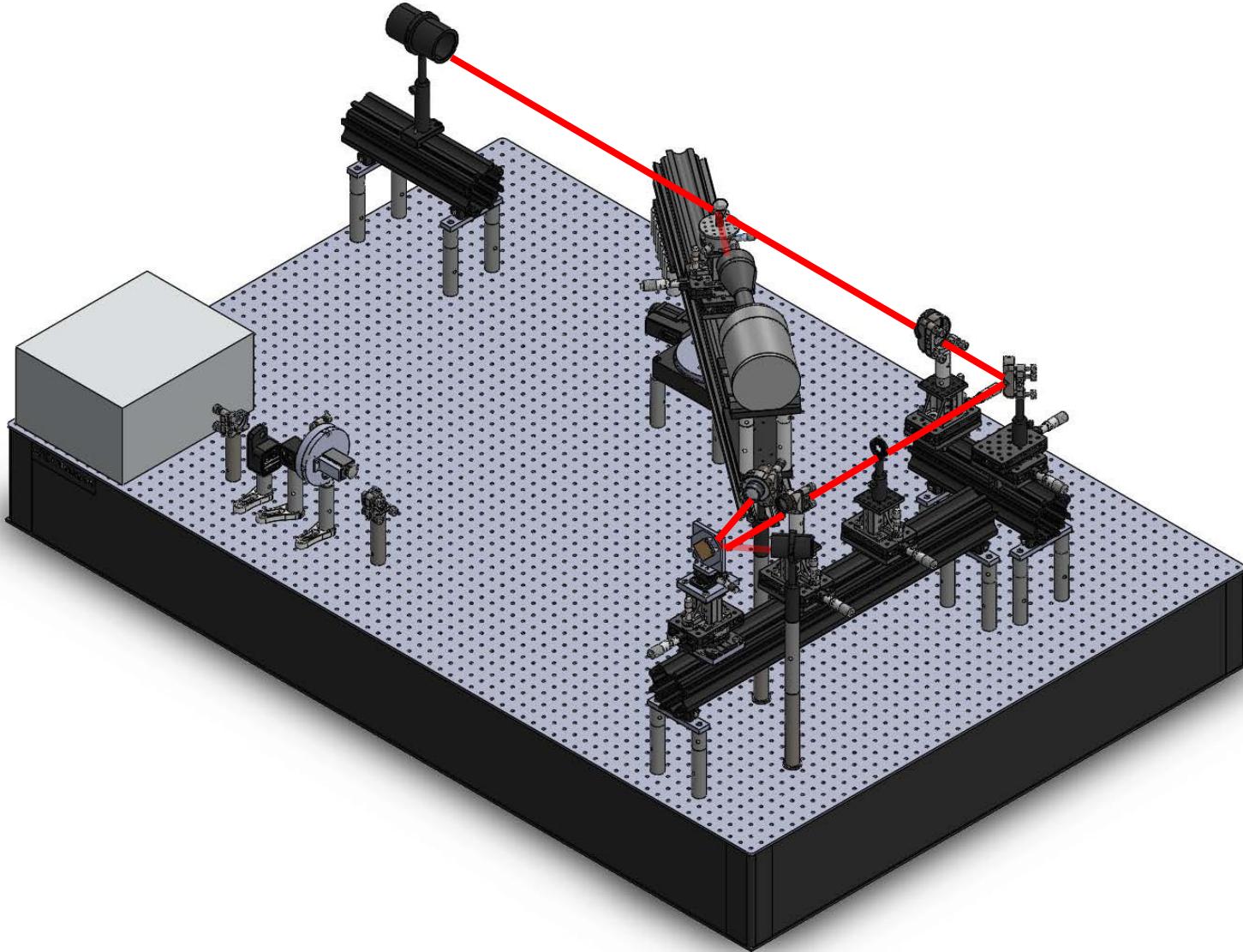
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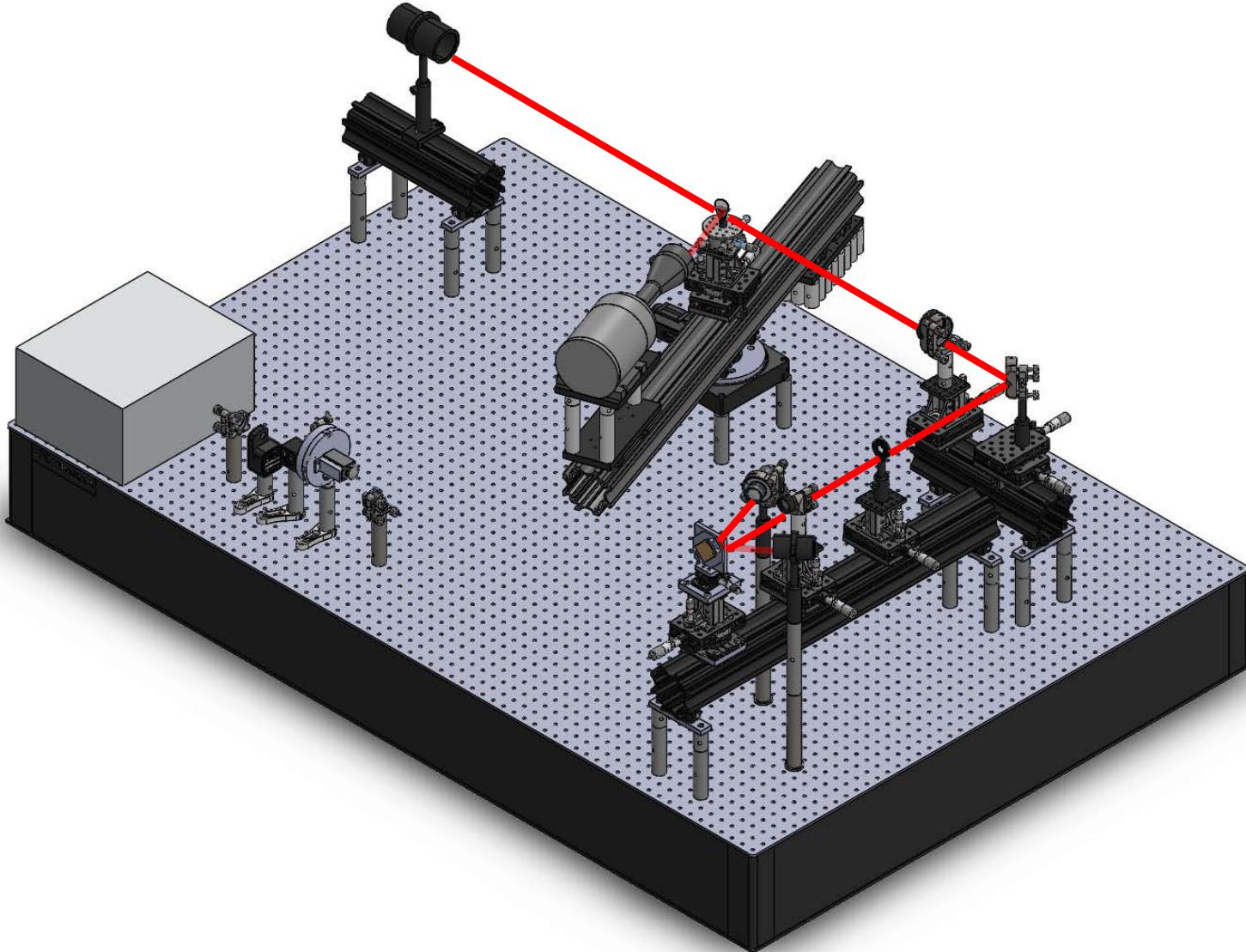
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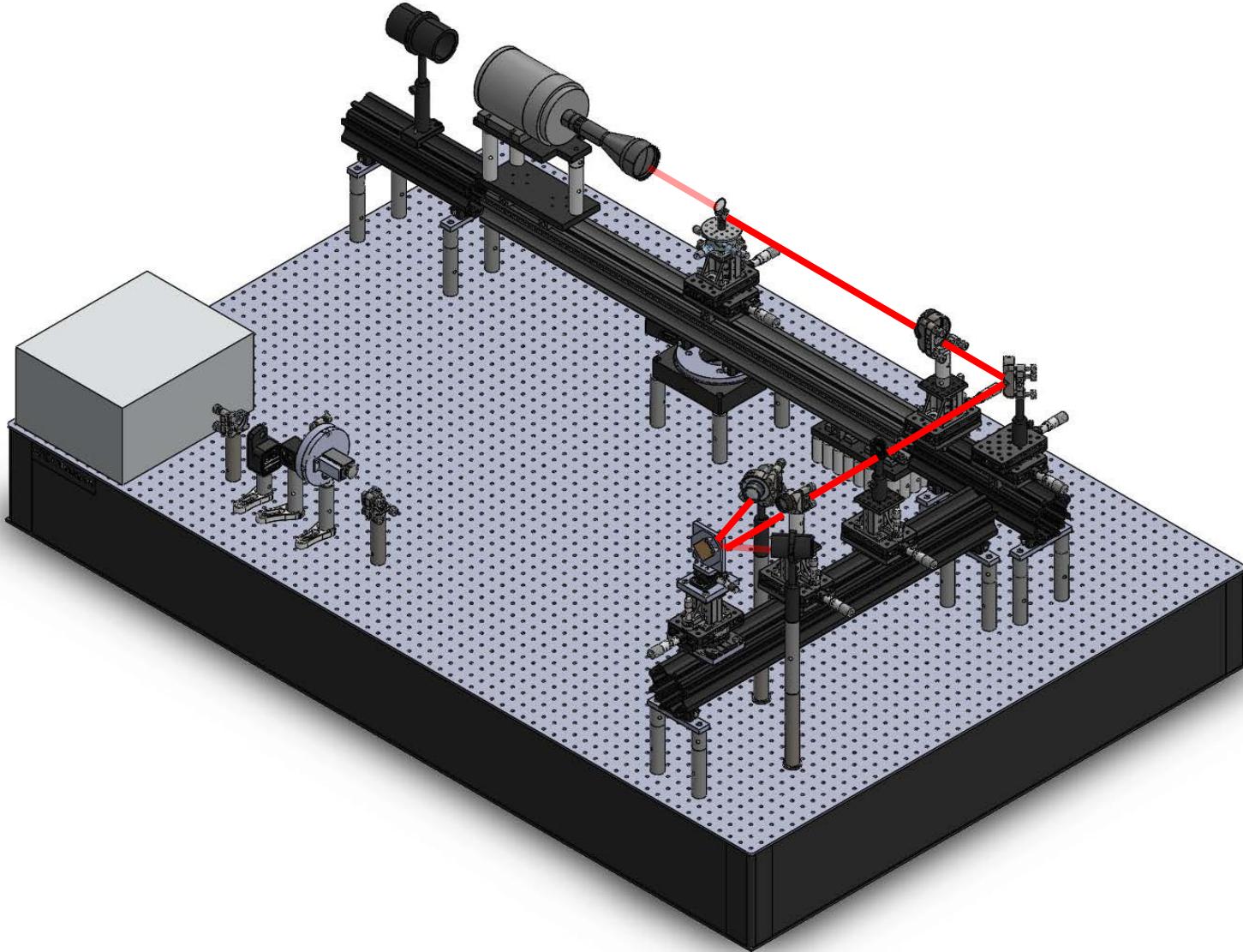
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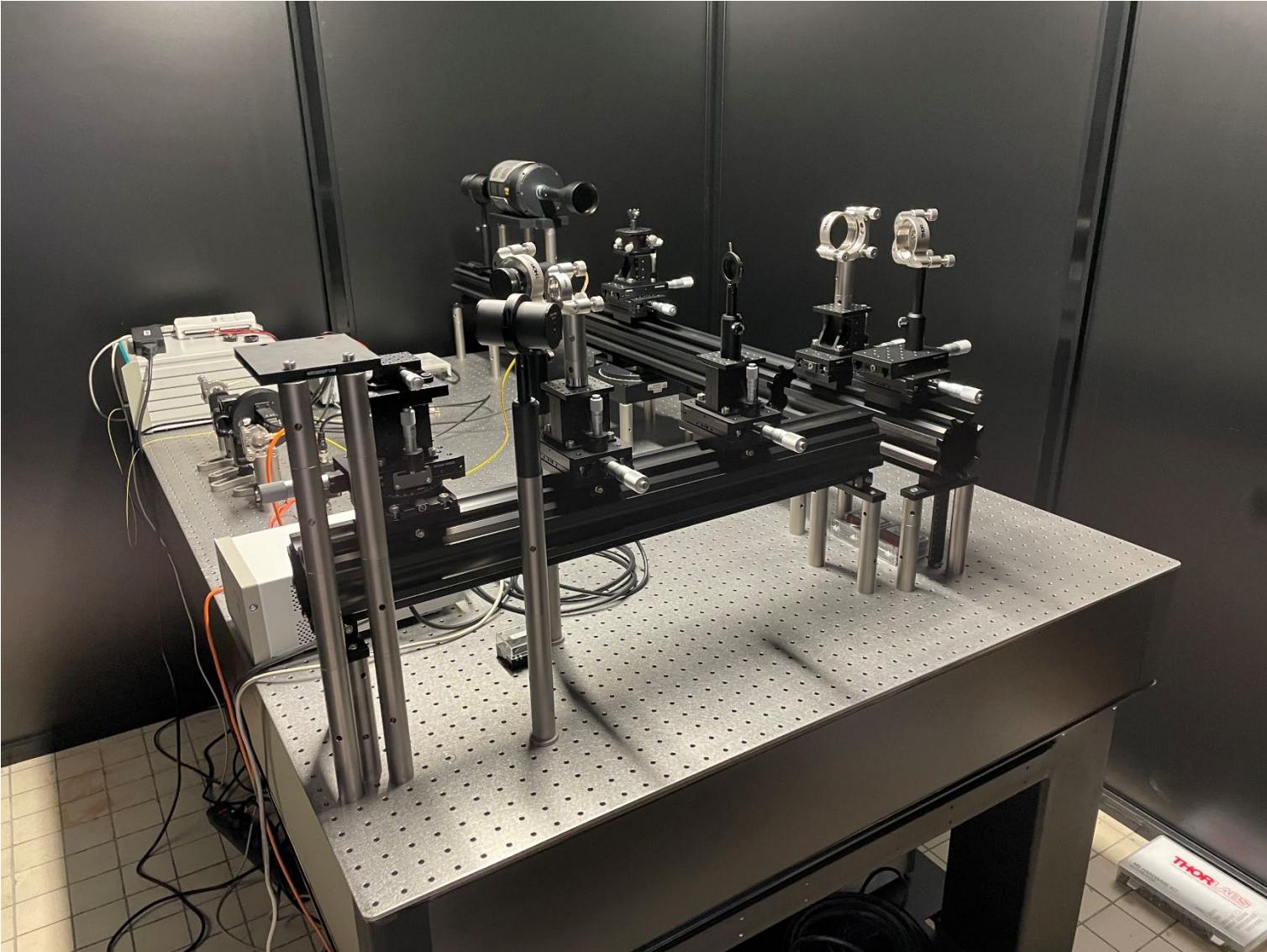
# SPARSE



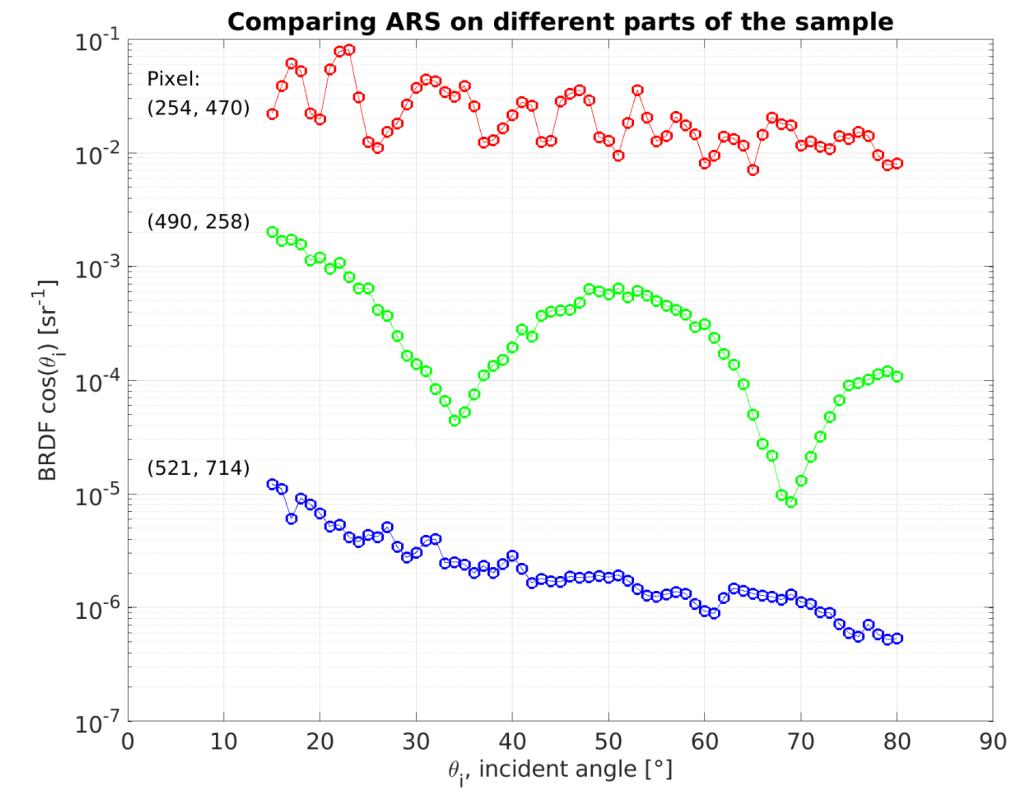
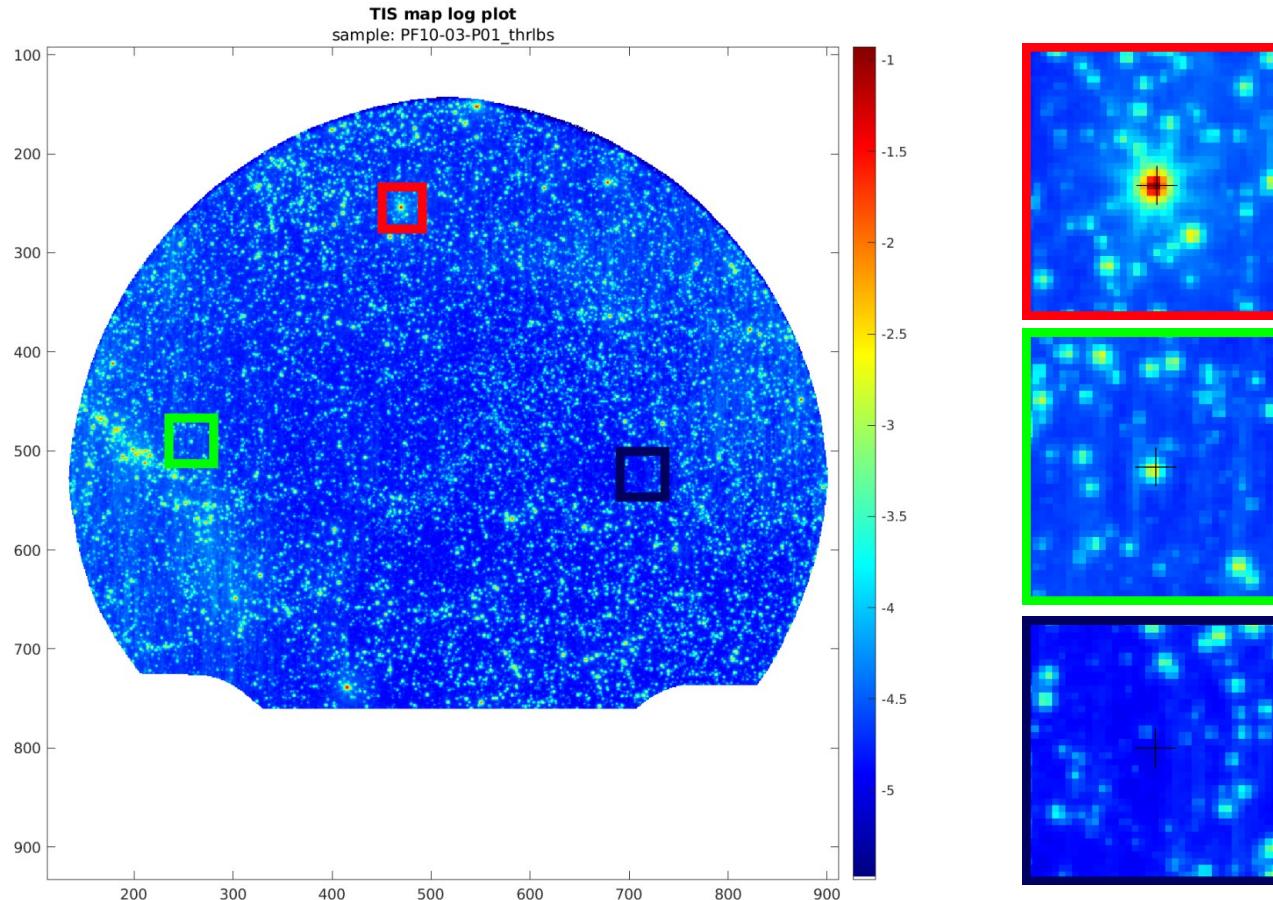
# SPARSE



# SPARSE



# SPARSE – Point Defects

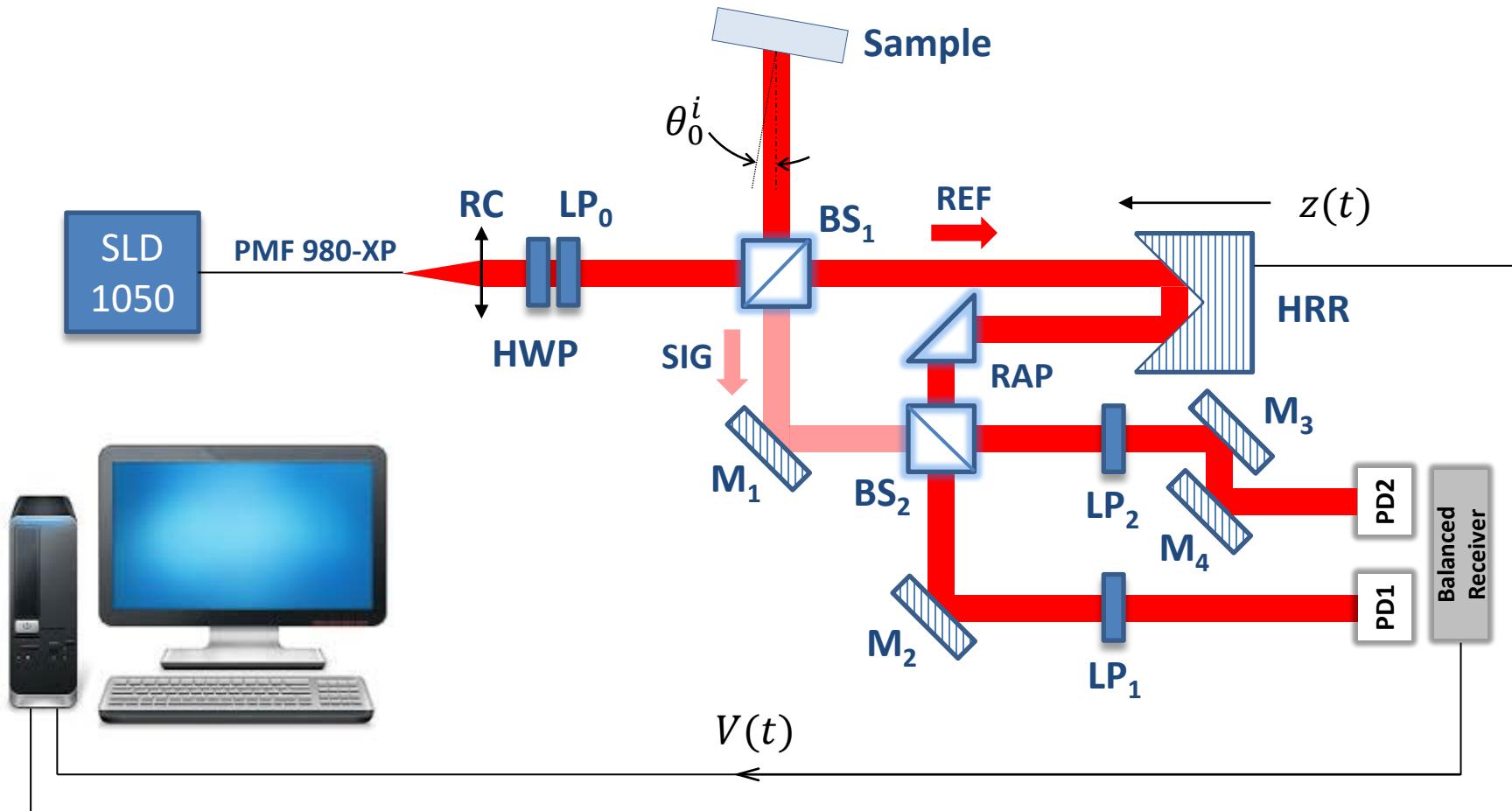


# SPARSE – Point Defects

- **Major planned improvements**

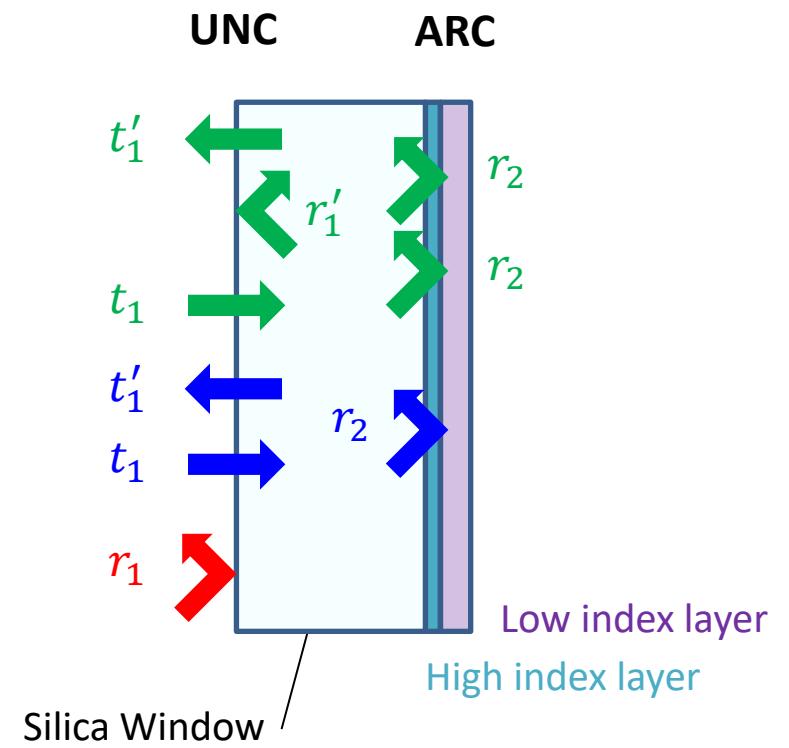
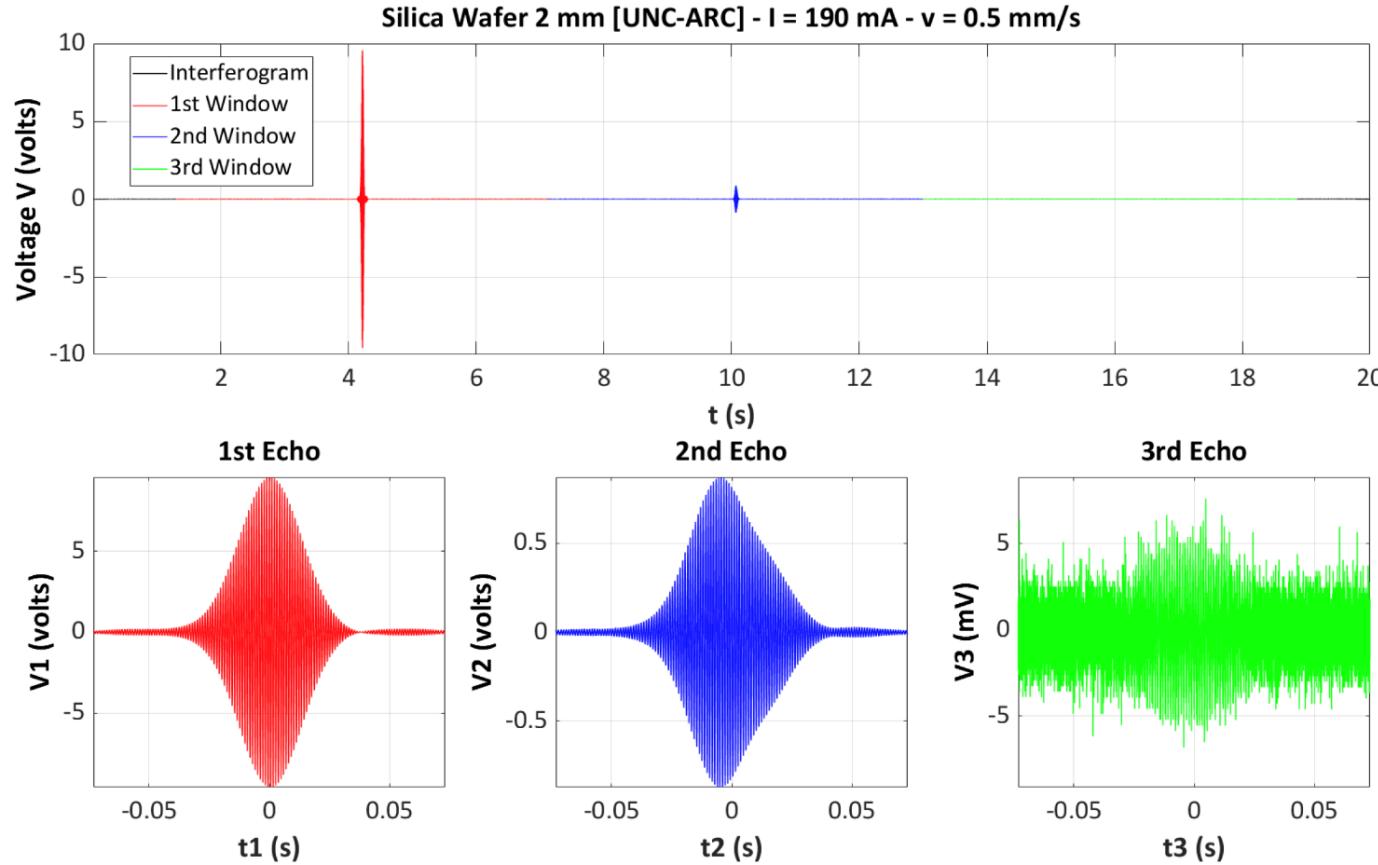
- *CCD camera with 2048 x 2048 pixels of 13 µm x 13 µm (4 million BRDF recorded in parallel)*
- *Low magnification telecentric objective (0.25X) with large pupil diameter (100 mm)*
- *High power light source (supercontinuum laser with wide bandwidth tunable filter)*
- *2-axis motorized sample holder to increase spatial field of view (400 mm x 400 mm, stitching)*

# BARRITON – Retroreflection and Backscattering



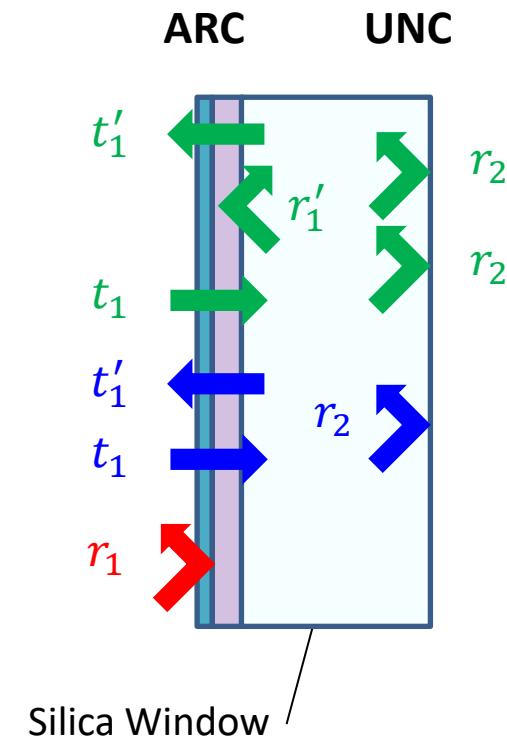
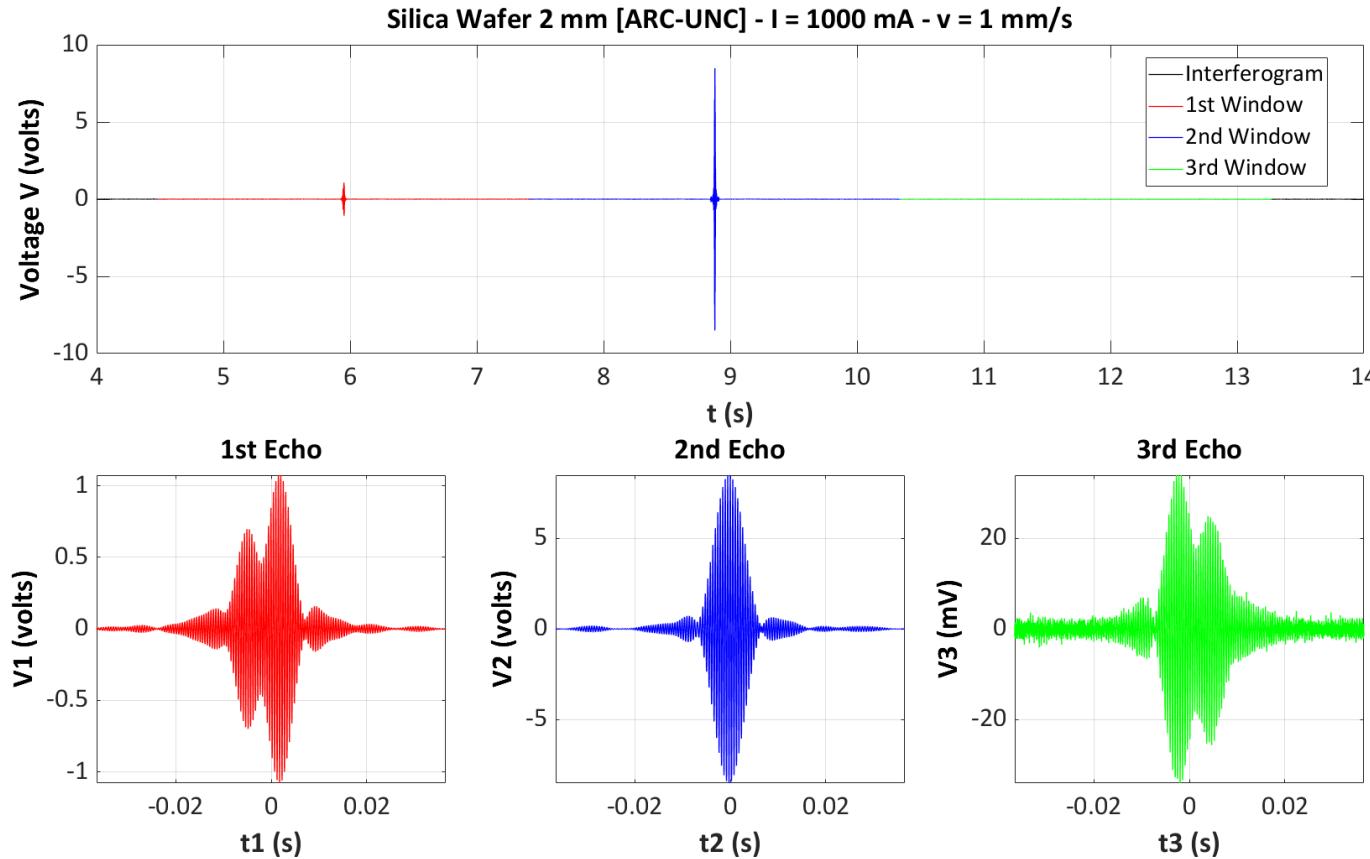
M. Lequime, I. Khan, M. Zerrad, and C. Amra, "Low coherence interferometric detection of the spectral dependence of the reflection coefficient of an anti-reflective coated interface," Opt. Express **31**, 8748-8774 (2023)

# BARRITON - Retroreflection



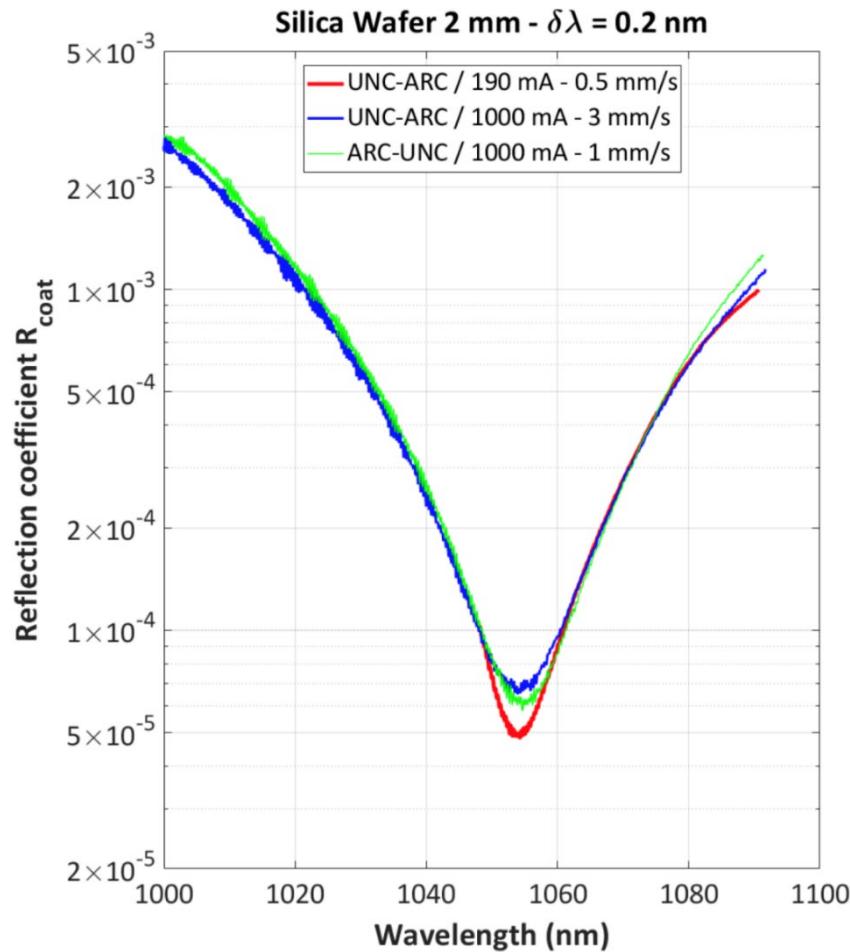
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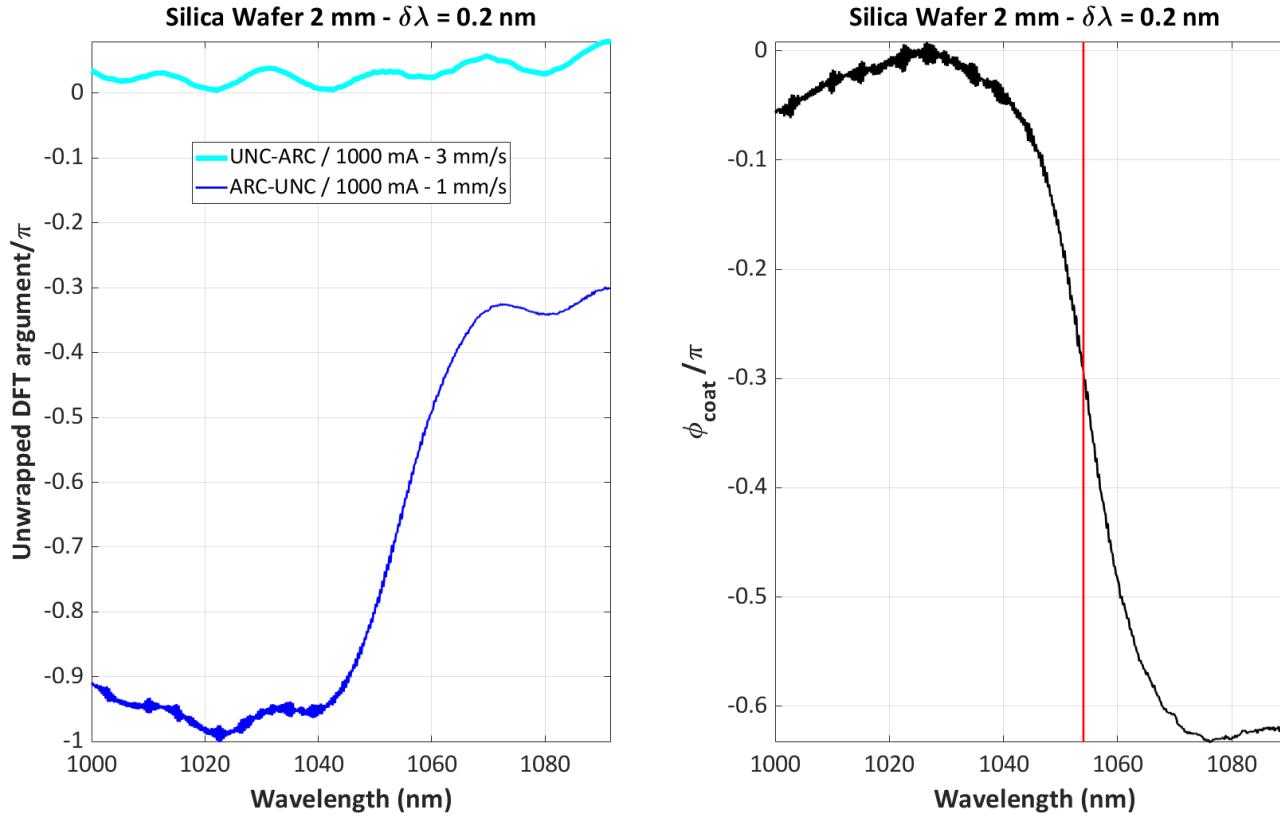
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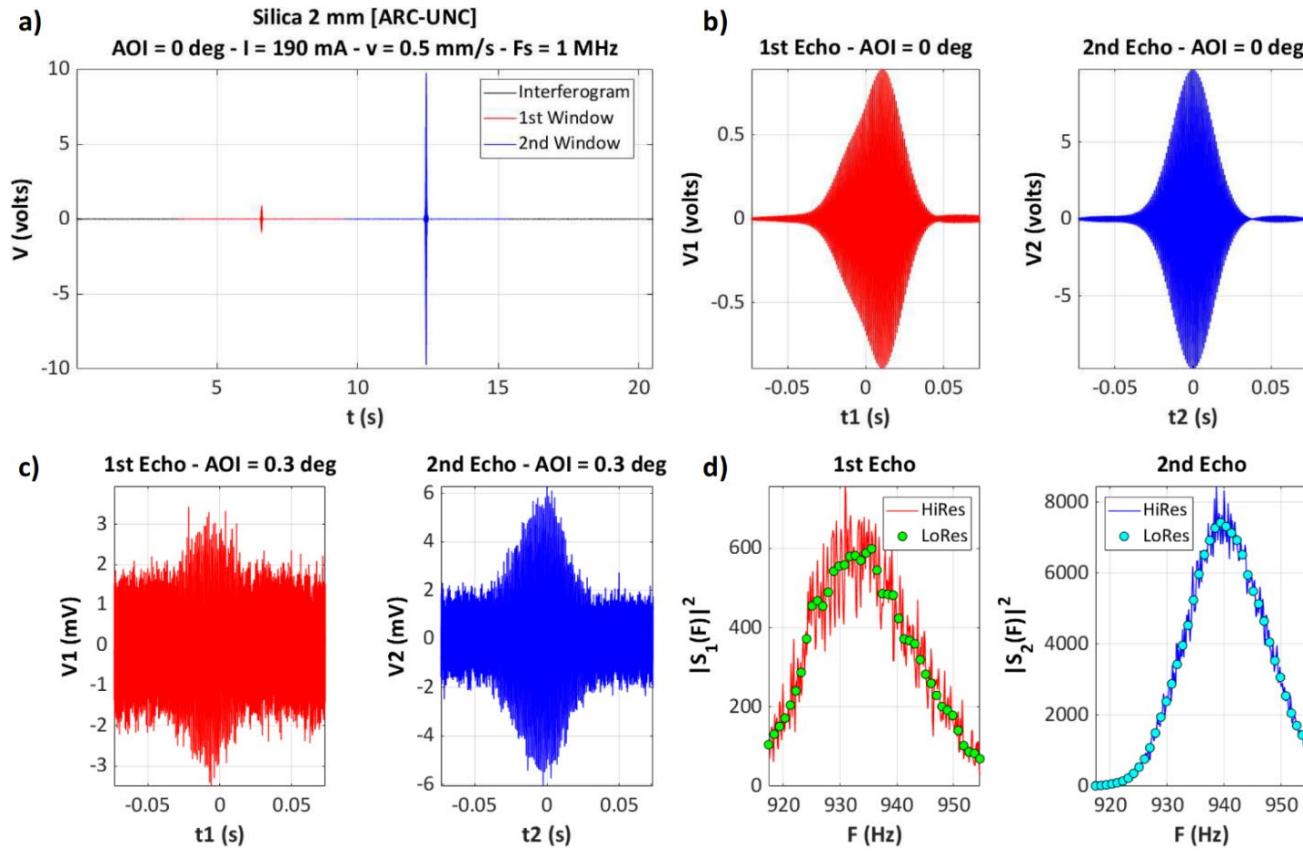
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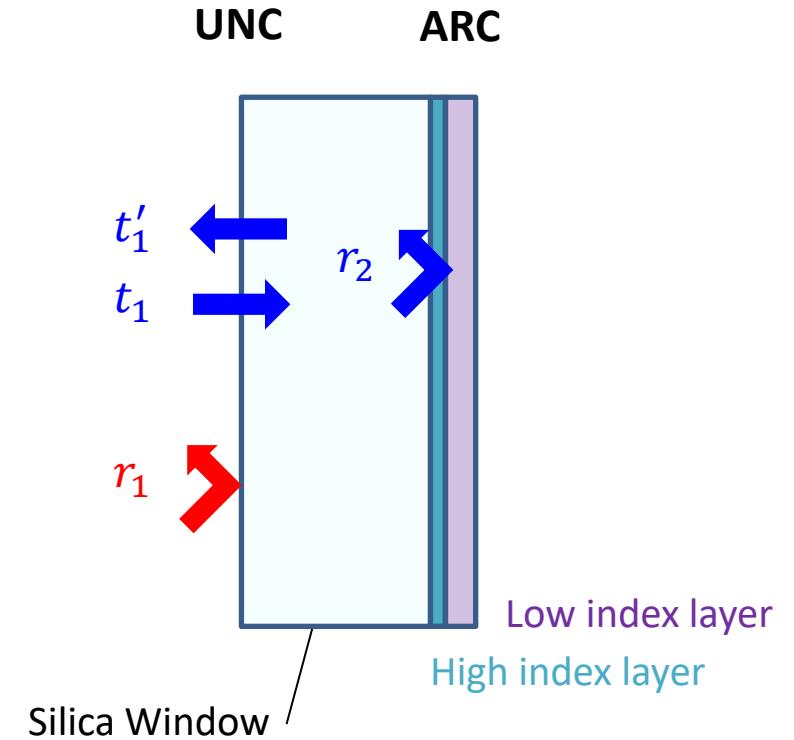
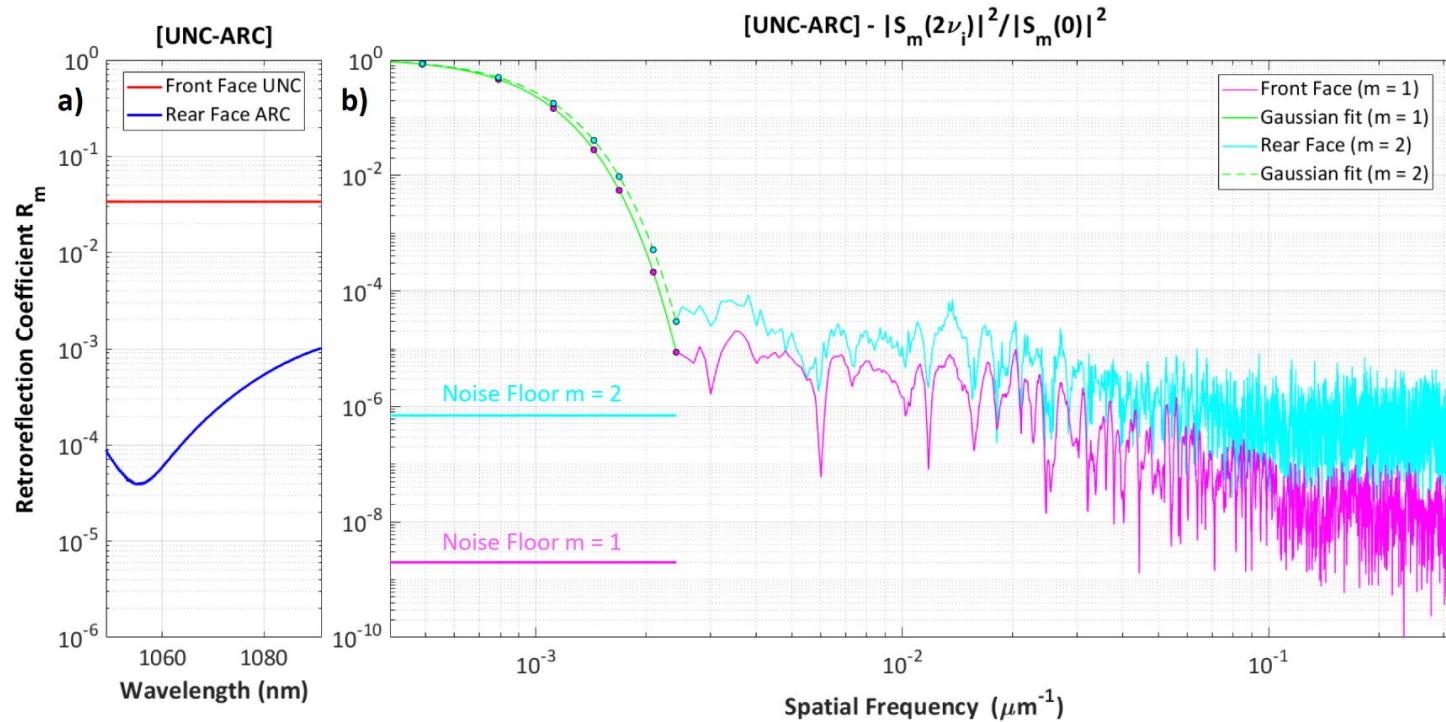
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# BARRITON – Retroreflection and Backscattering



M. Lequime, I. Khan, A. Boliand, M. Zerrad, and C. Amra, "Low-coherence interferometric measurement of the spatial frequency dependence of the light field backscattered by optical interfaces," Appl. Phys. Lett. **122**, 191103 (2023)

# BARRITON – Retroreflection and Backscattering



M. Lequime, I. Khan, A. Bolland, M. Zerrad, and C. Amra, "Low-coherence interferometric measurement of the spatial frequency dependence of the light field backscattered by optical interfaces," Appl. Phys. Lett. **122**, 191103 (2023)

# BARRITON – Retroreflection and Backscattering sources

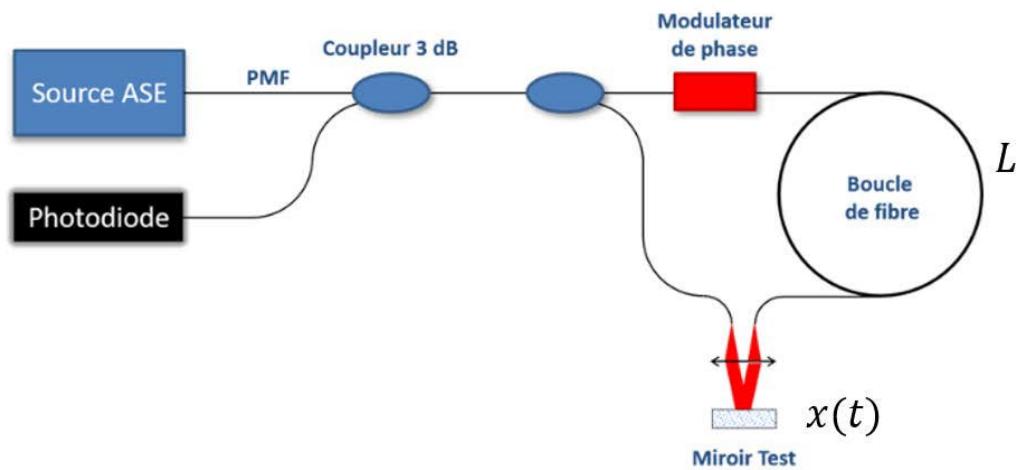
## ■ Major planned improvements

- *Extension of the OPD range (100 mm → several meters)*
- *Source coherence function cleanup (purchase of high quality components with high efficiency antireflective coatings)*
- *Increase of the ASE source power*
- *Use of an optical circulator operating in TE and TM polarization*

# GRAVITERM – Thermal noise

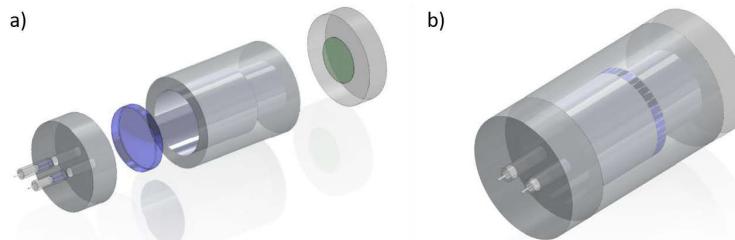
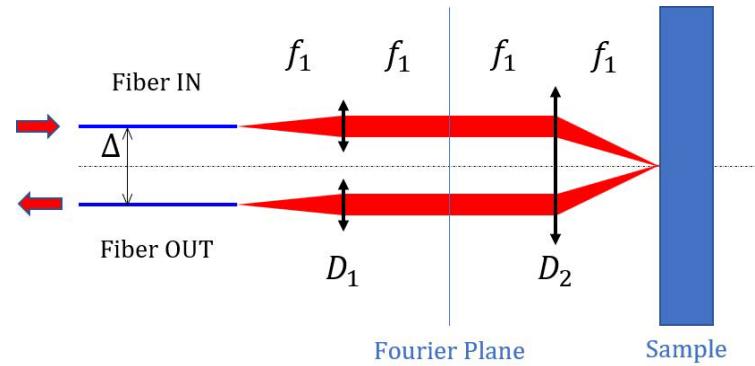
- **Use of a cyclic interferometer to record mirror thermal noise for gravitational wave detectors**
  - *Main advantage: Suppression of the influence of all reciprocal effects*
- **Key requirements**
  - *Direct measurement*
  - *Differential configuration (MIT setup spatially differential, here temporally differential)*
  - *Adjustment free*

# GRAVITERM – Thermal noise



$$\sigma_x = \frac{\lambda_0}{2\pi^2 f \tau} \sqrt{\frac{e}{2SP_e}}$$

$$\tau = \frac{nL}{c}$$



P. Rouquette, "L'interférométrie cyclique pour accéder au bruit thermique des miroirs pour les détecteurs d'ondes gravitationnelles" (2024)

# Conclusion

## ■ 3 key R&D topics

- *Develop an improved version of SPARSE capable of detecting the presence of point defects on the surface of a large diameter substrate, coated or uncoated, and determining the contribution of these defects to scattering loss budget.*
- *Develop an improved version of BARRITON capable of detecting the axial position and strength of retroreflection and/or backscatter sources along the optical axis of a large instrument.*
- *Development of a compact and adjustment free interferometric instrument for the measurement of the thermal noise of an optical interference coating (GRAVITERM).*